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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	HDMI-CEC, I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	39
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 13x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f051c8t7tr

1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32F051xx microcontrollers.

This document should be read in conjunction with the STM32F0xxxx reference manual (RM0091). The reference manual is available from the STMicroelectronics website *www.st.com*.

For information on the ARM® Cortex®-M0 core, please refer to the Cortex®-M0 Technical Reference Manual, available from the www.arm.com website.

Figure 8. LQFP32 package pinout

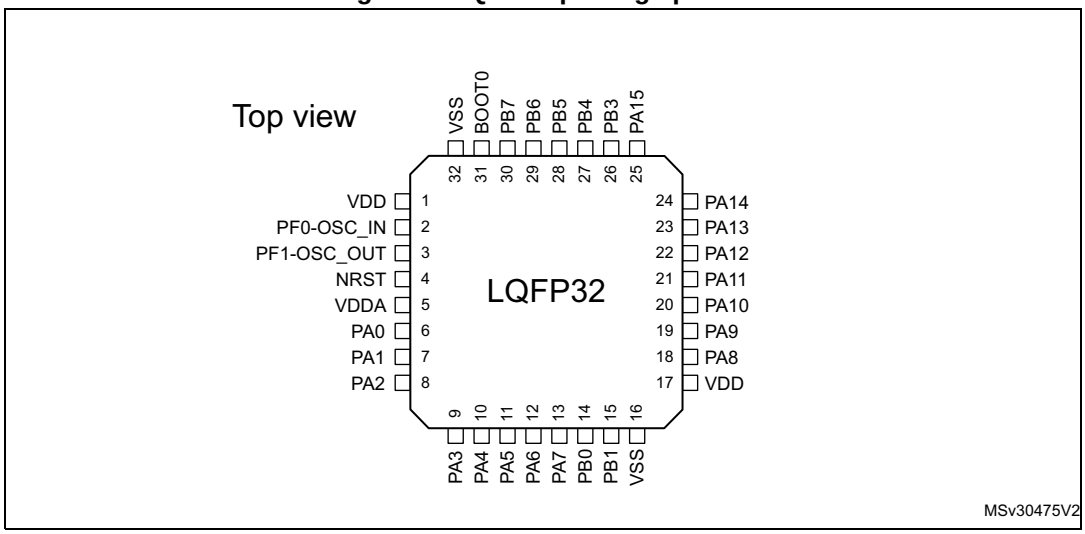


Figure 9. UFQFPN32 package pinout

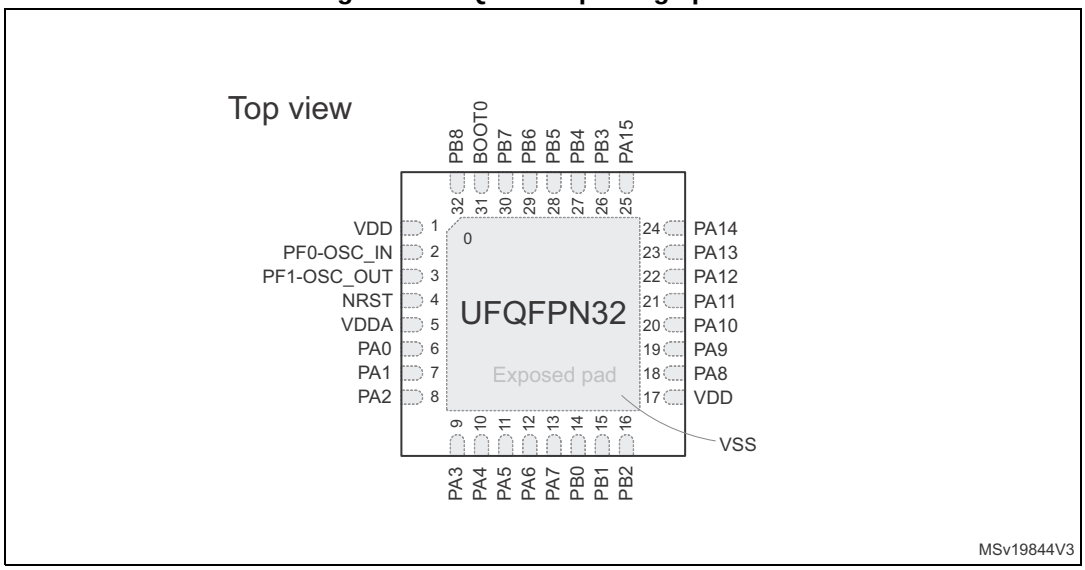


Table 12. Legend/abbreviations used in the pinout table

Name		Abbreviation	Definition
Pin name		Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
Pin type		S	Supply pin
		I	Input-only pin
		I/O	Input / output pin
I/O structure		FT	5 V-tolerant I/O
		FTf	5 V-tolerant I/O, FM+ capable
		TTa	3.3 V-tolerant I/O directly connected to ADC
		TC	Standard 3.3 V I/O
		B	Dedicated BOOT0 pin
		RST	Bidirectional reset pin with embedded weak pull-up resistor
Notes		Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset.	
Pin functions	Alternate functions	Functions selected through GPIOx_AFR registers	
	Additional functions	Functions directly selected/enabled through peripheral registers	

Table 13. Pin definitions

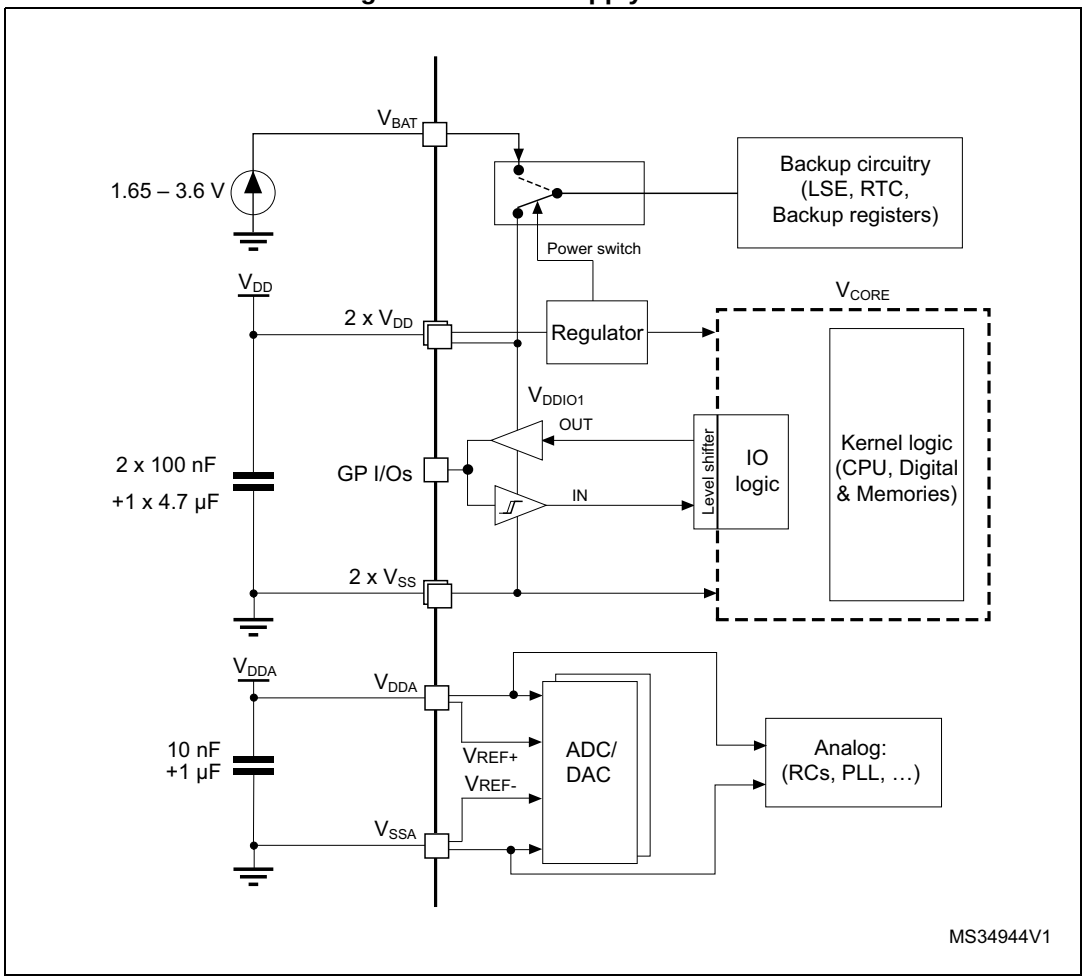
Pin number						Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	UFBGA64	LQFP48/UFQFPN48	WLCSP36	LQFP32	UFQFPN32					Alternate functions	Additional functions
1	B2	1	-	-	-	VBAT	S	-	-	Backup power supply	
2	A2	2	A6	-	-	PC13	I/O	TC	(1)(2)	-	RTC_TAMP1, RTC_TS, RTC_OUT, WKUP2
3	A1	3	B6	-	-	PC14-OSC32_IN (PC14)	I/O	TC	(1)(2)	-	OSC32_IN
4	B1	4	C6	-	-	PC15-OSC32_OUT (PC15)	I/O	TC	(1)(2)	-	OSC32_OUT
5	C1	5	B5	2	2	PF0-OSC_IN (PF0)	I/O	FT	-	-	OSC_IN
6	D1	6	C5	3	3	PF1-OSC_OUT (PF1)	I/O	FT	-	-	OSC_OUT

Table 14. Alternate functions selected through GPIOA_AFR registers for port A

Pin name	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
PA0	-	USART2_CTS	TIM2_CH1_ETR	TSC_G1_IO1		-	-	COMP1_OUT
PA1	EVENTOUT	USART2_RTS	TIM2_CH2	TSC_G1_IO2			-	-
PA2	TIM15_CH1	USART2_TX	TIM2_CH3	TSC_G1_IO3	-	-	-	COMP2_OUT
PA3	TIM15_CH2	USART2_RX	TIM2_CH4	TSC_G1_IO4	-	-	-	-
PA4	SPI1_NSS, I2S1_WS	USART2_CK	-	TSC_G2_IO1	TIM14_CH1	-	-	-
PA5	SPI1_SCK, I2S1_CK	CEC	TIM2_CH1_ETR	TSC_G2_IO2	-	-	-	-
PA6	SPI1_MISO, I2S1_MCK	TIM3_CH1	TIM1_BKIN	TSC_G2_IO3		TIM16_CH1	EVENTOUT	COMP1_OUT
PA7	SPI1_MOSI, I2S1_SD	TIM3_CH2	TIM1_CH1N	TSC_G2_IO4	TIM14_CH1	TIM17_CH1	EVENTOUT	COMP2_OUT
PA8	MCO	USART1_CK	TIM1_CH1	EVENTOUT		-	-	-
PA9	TIM15_BKIN	USART1_TX	TIM1_CH2	TSC_G4_IO1	-	-	-	-
PA10	TIM17_BKIN	USART1_RX	TIM1_CH3	TSC_G4_IO2	-	-	-	-
PA11	EVENTOUT	USART1_CTS	TIM1_CH4	TSC_G4_IO3	-	-	-	COMP1_OUT
PA12	EVENTOUT	USART1_RTS	TIM1_ETR	TSC_G4_IO4	-	-	-	COMP2_OUT
PA13	SWDIO	IR_OUT		-	-	-	-	-
PA14	SWCLK	USART2_TX	-	-	-	-	-	-
PA15	SPI1_NSS, I2S1_WS	USART2_RX	TIM2_CH1_ETR	EVENTOUT		-	-	-

6.1.6 Power supply scheme

Figure 13. Power supply scheme



Caution: Each power supply pair (V_{DD}/V_{SS}, V_{DDA}/V_{SSA} etc.) must be decoupled with filtering ceramic capacitors as shown above. These capacitors must be placed as close as possible to, or below, the appropriate pins on the underside of the PCB to ensure the good functionality of the device.

Table 28. Typical and maximum current consumption from the V_{BAT} supply

Symbol	Parameter	Conditions	Typ @ V_{BAT}						Max(1)			Unit
			1.65 V	1.8 V	2.4 V	2.7 V	3.3 V	3.6 V	T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD_VBAT}	RTC domain supply current	LSE & RTC ON; “Xtal mode”: lower driving capability; LSEDRV[1:0] = '00'	0.5	0.5	0.6	0.7	0.8	0.9	1.0	1.3	1.7	µA
		LSE & RTC ON; “Xtal mode” higher driving capability; LSEDRV[1:0] = '11'	0.8	0.8	0.9	1.0	1.1	1.2	1.3	1.6	2.1	

1. Data based on characterization results, not tested in production.

Typical current consumption

The MCU is placed under the following conditions:

- $V_{DD} = V_{DDA} = 3.3$ V
- All I/O pins are in analog input configuration
- The Flash memory access time is adjusted to f_{HCLK} frequency:
  - 0 wait state and Prefetch OFF from 0 to 24 MHz
  - 1 wait state and Prefetch ON above 24 MHz
- When the peripherals are enabled, $f_{PCLK} = f_{HCLK}$
- PLL is used for frequencies greater than 8 MHz
- AHB prescaler of 2, 4, 8 and 16 is used for the frequencies 4 MHz, 2 MHz, 1 MHz and 500 kHz respectively

trigger circuits used to discriminate the input value. Unless this specific configuration is required by the application, this supply current consumption can be avoided by configuring these I/Os in analog mode. This is notably the case of ADC input pins which should be configured as analog inputs.

Caution: Any floating input pin can also settle to an intermediate voltage level or switch inadvertently, as a result of external electromagnetic noise. To avoid current consumption related to floating pins, they must either be configured in analog mode, or forced internally to a definite digital value. This can be done either by using pull-up/down resistors or by configuring the pins in output mode.

I/O dynamic current consumption

In addition to the internal peripheral current consumption measured previously (see *Table 31: Peripheral current consumption*), the I/Os used by an application also contribute to the current consumption. When an I/O pin switches, it uses the current from the I/O supply voltage to supply the I/O pin circuitry and to charge/discharge the capacitive load (internal or external) connected to the pin:

$$I_{SW} = V_{DDIOx} \times f_{SW} \times C$$

where

I_{SW} is the current sunk by a switching I/O to charge/discharge the capacitive load

V_{DDIOx} is the I/O supply voltage

f_{SW} is the I/O switching frequency

C is the total capacitance seen by the I/O pin: $C = C_{INT} + C_{EXT} + C_S$

C_S is the PCB board capacitance including the pad pin.

The test pin is configured in push-pull output mode and is toggled by software at a fixed frequency.

Table 30. Switching output I/O current consumption

Symbol	Parameter	Conditions[1]	I/O toggling frequency (f_{SW})	Typ	Unit
I_{SW}	I/O current consumption	V_{DDIOx} = 3.3 V C =C_{INT}	4 MHz	0.07	mA
			8 MHz	0.15	
			16 MHz	0.31	
			24 MHz	0.53	
			48 MHz	0.92	
		V_{DDIOx} = 3.3 V C_{EXT} = 0 pF C = C_{INT} + C_{EXT}+ C_S	4 MHz	0.18	
			8 MHz	0.37	
			16 MHz	0.76	
			24 MHz	1.39	
			48 MHz	2.188	
		V_{DDIOx} = 3.3 V C_{EXT} = 10 pF C = C_{INT} + C_{EXT}+ C_S	4 MHz	0.32	
			8 MHz	0.64	
			16 MHz	1.25	
			24 MHz	2.23	
			48 MHz	4.442	
		V_{DDIOx} = 3.3 V C_{EXT} = 22 pF C = C_{INT} + C_{EXT}+ C_S	4 MHz	0.49	
			8 MHz	0.94	
			16 MHz	2.38	
			24 MHz	3.99	
		V_{DDIOx} = 3.3 V C_{EXT} = 33 pF C = C_{INT} + C_{EXT}+ C_S	4 MHz	0.64	
			8 MHz	1.25	
			16 MHz	3.24	
			24 MHz	5.02	
		V_{DDIOx} = 3.3 V C_{EXT} = 47 pF C = C_{INT} + C_{EXT}+ C_S C = C_{int}	4 MHz	0.81	
			8 MHz	1.7	
			16 MHz	3.67	
		V_{DDIOx} = 2.4 V C_{EXT} = 47 pF C = C_{INT} + C_{EXT}+ C_S C = C_{int}	4 MHz	0.66	
			8 MHz	1.43	
			16 MHz	2.45	
			24 MHz	4.97	

1. C_S = 7 pF (estimated value).

6.3.6 Wakeup time from low-power mode

The wakeup times given in *Table 32* are the latency between the event and the execution of the first user instruction. The device goes in low-power mode after the WFE (Wait For Event) instruction, in the case of a WFI (Wait For Interruption) instruction, 16 CPU cycles must be added to the following timings due to the interrupt latency in the Cortex M0 architecture.

The SYSCLK clock source setting is kept unchanged after wakeup from Sleep mode. During wakeup from Stop or Standby mode, SYSCLK takes the default setting: HSI 8 MHz.

The wakeup source from Sleep and Stop mode is an EXTI line configured in event mode. The wakeup source from Standby mode is the WKUP1 pin (PA0).

All timings are derived from tests performed under the ambient temperature and supply voltage conditions summarized in *Table 20: General operating conditions*.

Table 32. Low-power mode wakeup timings

Symbol	Parameter	Conditions	Typ @V_{DD} = V_{DDA}					Max	Unit
			= 2.0 V	= 2.4 V	= 2.7 V	= 3 V	= 3.3 V		
t_{WUSTOP}	Wakeup from Stop mode	Regulator in run mode	3.2	3.1	2.9	2.9	2.8	5	µs
		Regulator in low power mode	7.0	5.8	5.2	4.9	4.6	9	
$t_{WUSTANDBY}$	Wakeup from Standby mode	-	60.4	55.6	53.5	52	51	-	
$t_{WUSLEEP}$	Wakeup from Sleep mode	-	4 SYSCLK cycles					-	

6.3.7 External clock source characteristics

High-speed external user clock generated from an external source

In bypass mode the HSE oscillator is switched off and the input pin is a standard GPIO.

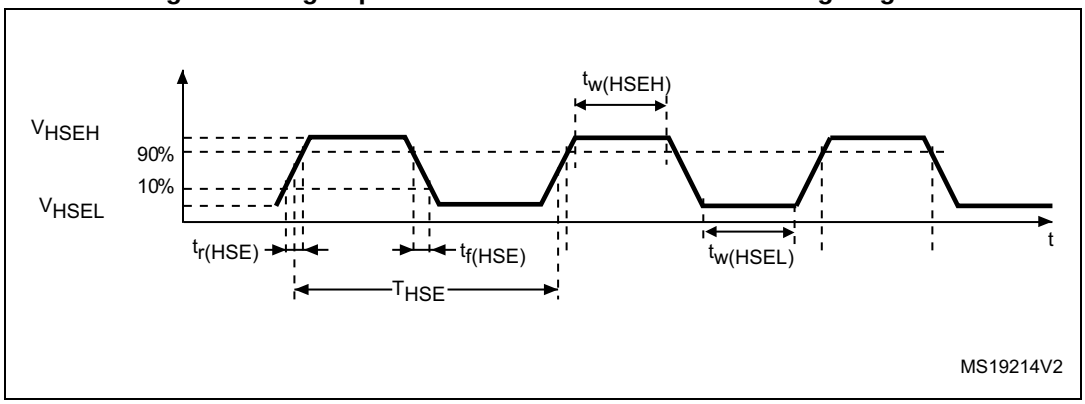
The external clock signal has to respect the I/O characteristics in *Section 6.3.14*. However, the recommended clock input waveform is shown in *Figure 15: High-speed external clock source AC timing diagram*.

Table 33. High-speed external user clock characteristics

Symbol	Parameter(1)	Min	Typ	Max	Unit
f_{HSE_ext}	User external clock source frequency	-	8	32	MHz
V_{HSEH}	OSC_IN input pin high level voltage	0.7 V_{DDIOx}	-	V_{DDIOx}	V
V_{HSEL}	OSC_IN input pin low level voltage	V_{SS}	-	0.3 V_{DDIOx}	
$t_{w(HSEH)}$ $t_{w(HSEL)}$	OSC_IN high or low time	15	-	-	ns
$t_{r(HSE)}$ $t_{f(HSE)}$	OSC_IN rise or fall time	-	-	20	

1. Guaranteed by design, not tested in production.

Figure 15. High-speed external clock source AC timing diagram



Low-speed external user clock generated from an external source

In bypass mode the LSE oscillator is switched off and the input pin is a standard GPIO.

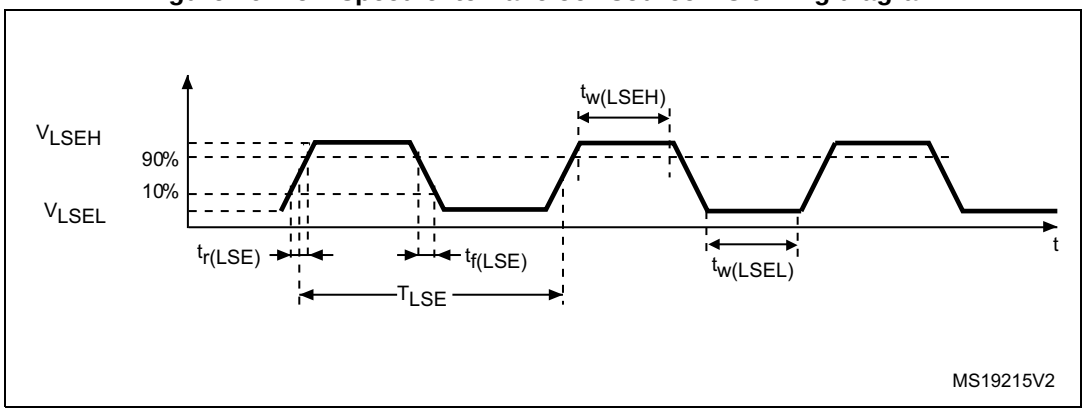
The external clock signal has to respect the I/O characteristics in *Section 6.3.14*. However, the recommended clock input waveform is shown in *Figure 16*.

Table 34. Low-speed external user clock characteristics

Symbol	Parameter(1)	Min	Typ	Max	Unit
f_{LSE_ext}	User external clock source frequency	-	32.768	1000	kHz
V_{LSEH}	OSC32_IN input pin high level voltage	0.7 V_{DDIOx}	-	V_{DDIOx}	V
V_{LSEL}	OSC32_IN input pin low level voltage	V_{SS}	-	0.3 V_{DDIOx}	
$t_{w(LSEH)}$ $t_{w(LSEL)}$	OSC32_IN high or low time	450	-	-	ns
$t_{r(LSE)}$ $t_{f(LSE)}$	OSC32_IN rise or fall time	-	-	50	

1. Guaranteed by design, not tested in production.

Figure 16. Low-speed external clock source AC timing diagram



Low-speed internal (LSI) RC oscillator

Table 39. LSI oscillator characteristics(1)

Symbol	Parameter	Min	Typ	Max	Unit
f_{LSI}	Frequency	30	40	50	kHz
$t_{su(LSI)}$(2)	LSI oscillator startup time	-	-	85	µs
$I_{DDA(LSI)}$(2)	LSI oscillator power consumption	-	0.75	1.2	µA

1. V_{DDA} = 3.3 V, T_A = –40 to 105 °C unless otherwise specified.
2. Guaranteed by design, not tested in production.

6.3.9 PLL characteristics

The parameters given in *Table 40* are derived from tests performed under ambient temperature and supply voltage conditions summarized in *Table 20: General operating conditions*.

Table 40. PLL characteristics

Symbol	Parameter	Value			Unit
		Min	Typ	Max	
f_{PLL_IN}	PLL input clock(1)	1(2)	8.0	24(2)	MHz
	PLL input clock duty cycle	40(2)	-	60(2)	%
f_{PLL_OUT}	PLL multiplier output clock	16(2)	-	48	MHz
t_{LOCK}	PLL lock time	-	-	200(2)	µs
$Jitter_{PLL}$	Cycle-to-cycle jitter	-	-	300(2)	ps

1. Take care to use the appropriate multiplier factors to obtain PLL input clock values compatible with the range defined by f_{PLL_OUT}.
2. Guaranteed by design, not tested in production.

6.3.10 Memory characteristics

Flash memory

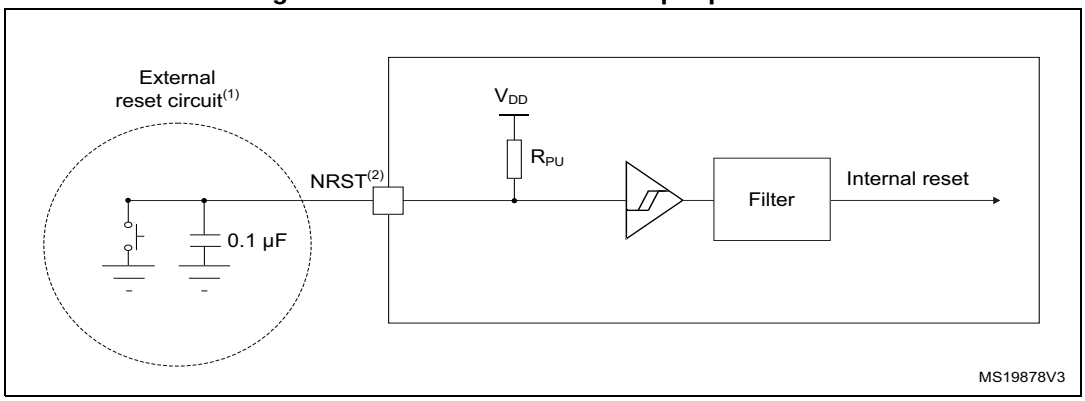
The characteristics are given at T_A = –40 to 105 °C unless otherwise specified.

Table 41. Flash memory characteristics

Symbol	Parameter	Conditions	Min	Typ	Max(1)	Unit
t_{prog}	16-bit programming time	T_A = - 40 to +105 °C	40	53.5	60	µs
t_{ERASE}	Page (1 KB) erase time	T_A = - 40 to +105 °C	20	-	40	ms
t_{ME}	Mass erase time	T_A = - 40 to +105 °C	20	-	40	ms
I_{DD}	Supply current	Write mode	-	-	10	mA
		Erase mode	-	-	12	mA

1. Guaranteed by design, not tested in production.

Figure 24. Recommended NRST pin protection



1. The external capacitor protects the device against parasitic resets.
2. The user must ensure that the level on the NRST pin can go below the $V_{IL(NRST)}$ max level specified in *Table 51: NRST pin characteristics*. Otherwise the reset will not be taken into account by the device.

6.3.16 12-bit ADC characteristics

Unless otherwise specified, the parameters given in *Table 52* are derived from tests performed under the conditions summarized in *Table 20: General operating conditions*.

Note: It is recommended to perform a calibration after each power-up.

Table 52. ADC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage for ADC ON	-	2.4	-	3.6	V
$I_{DDA\ (ADC)}$	Current consumption of the ADC(1)	V_{DDA} = 3.3 V	-	0.9	-	mA
f_{ADC}	ADC clock frequency	-	0.6	-	14	MHz
f_S(2)	Sampling rate	12-bit resolution	0.043	-	1	MHz
f_{TRIG}(2)	External trigger frequency	f_{ADC} = 14 MHz, 12-bit resolution	-	-	823	kHz
		12-bit resolution	-	-	17	$1/f_{ADC}$
V_{AIN}	Conversion voltage range	-	0	-	V_{DDA}	V
R_{AIN}(2)	External input impedance	See *Equation 1* and *Table 53* for details	-	-	50	kΩ
R_{ADC}(2)	Sampling switch resistance	-	-	-	1	kΩ
C_{ADC}(2)	Internal sample and hold capacitor	-	-	-	8	pF
t_{CAL}(2)(3)	Calibration time	f_{ADC} = 14 MHz	5.9			µs
		-	83			$1/f_{ADC}$

6.3.17 DAC electrical specifications

Table 55. DAC characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Comments
V_{DDA}	Analog supply voltage for DAC ON	2.4	-	3.6	V	-
R_{LOAD}(1)	Resistive load with buffer ON	5	-	-	kΩ	Load connected to V_{SSA}
		25	-	-	kΩ	Load connected to V_{DDA}
R_O(1)	Impedance output with buffer OFF	-	-	15	kΩ	When the buffer is OFF, the Minimum resistive load between DAC_OUT and V_{SS} to have a 1% accuracy is 1.5 MΩ
C_{LOAD}(1)	Capacitive load	-	-	50	pF	Maximum capacitive load at DAC_OUT pin (when the buffer is ON).
DAC_OUT min(1)	Lower DAC_OUT voltage with buffer ON	0.2	-	-	V	It gives the maximum output excursion of the DAC. It corresponds to 12-bit input code (0x0E0) to (0xF1C) at V_{DDA} = 3.6 V and (0x155) and (0xEAB) at V_{DDA} = 2.4 V
DAC_OUT max(1)	Higher DAC_OUT voltage with buffer ON	-	-	V_{DDA} – 0.2	V	
DAC_OUT min(1)	Lower DAC_OUT voltage with buffer OFF	-	0.5	-	mV	It gives the maximum output excursion of the DAC.
DAC_OUT max(1)	Higher DAC_OUT voltage with buffer OFF	-	-	V_{DDA} – 1LSB	V	
I_{DDA}(1)	DAC DC current consumption in quiescent mode(2)	-	-	600	µA	With no load, middle code (0x800) on the input
		-	-	700	µA	With no load, worst code (0xF1C) on the input
DNL(3)	Differential non linearity Difference between two consecutive code-1LSB)	-	-	±0.5	LSB	Given for the DAC in 10-bit configuration
		-	-	±2	LSB	Given for the DAC in 12-bit configuration
INL(3)	Integral non linearity (difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 1023)	-	-	±1	LSB	Given for the DAC in 10-bit configuration
		-	-	±4	LSB	Given for the DAC in 12-bit configuration
Offset(3)	Offset error (difference between measured value at Code (0x800) and the ideal value = V_{DDA}/2)	-	-	±10	mV	-
		-	-	±3	LSB	Given for the DAC in 10-bit at V_{DDA} = 3.6 V
		-	-	±12	LSB	Given for the DAC in 12-bit at V_{DDA} = 3.6 V

Figure 29. SPI timing diagram - slave mode and CPHA = 0

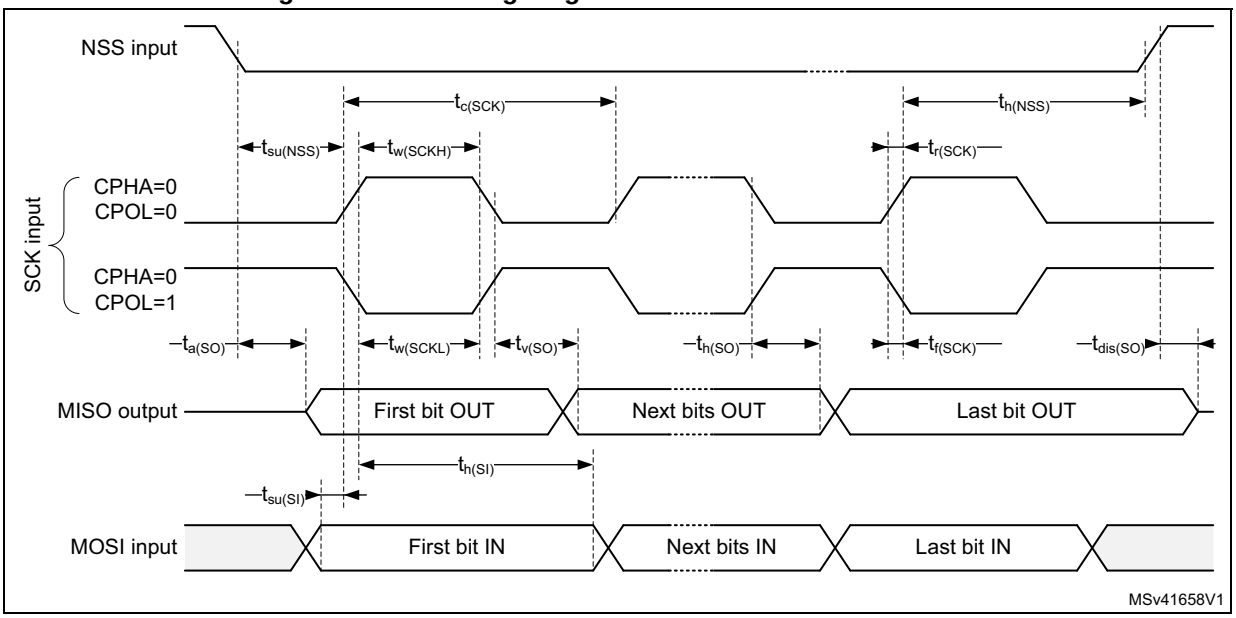
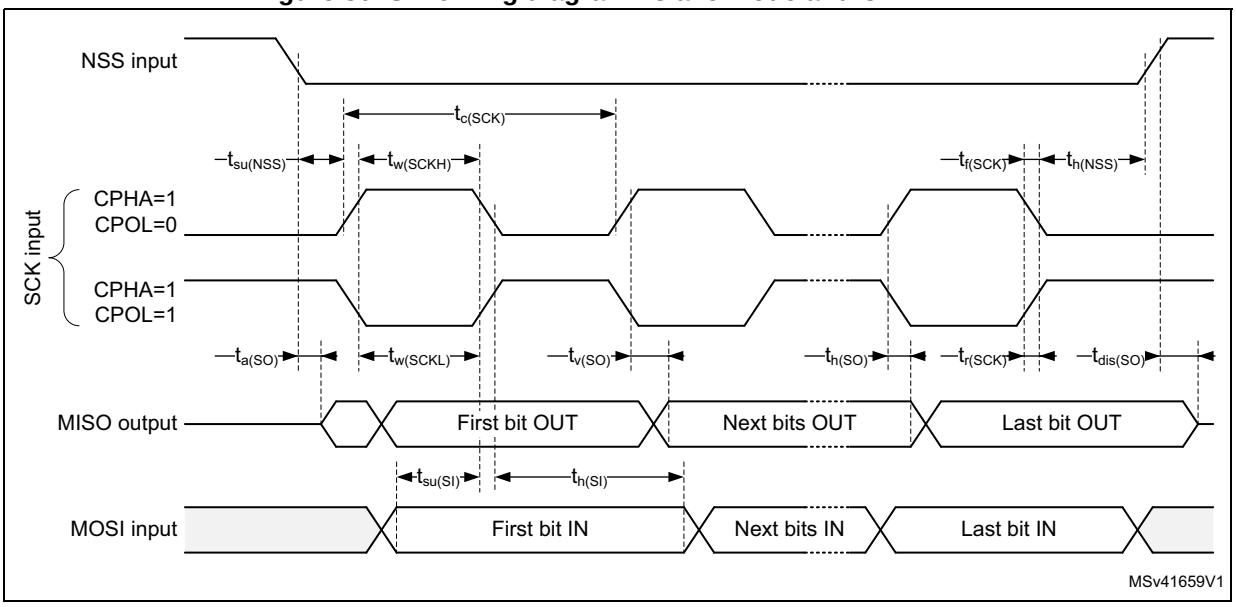


Figure 30. SPI timing diagram - slave mode and CPHA = 1



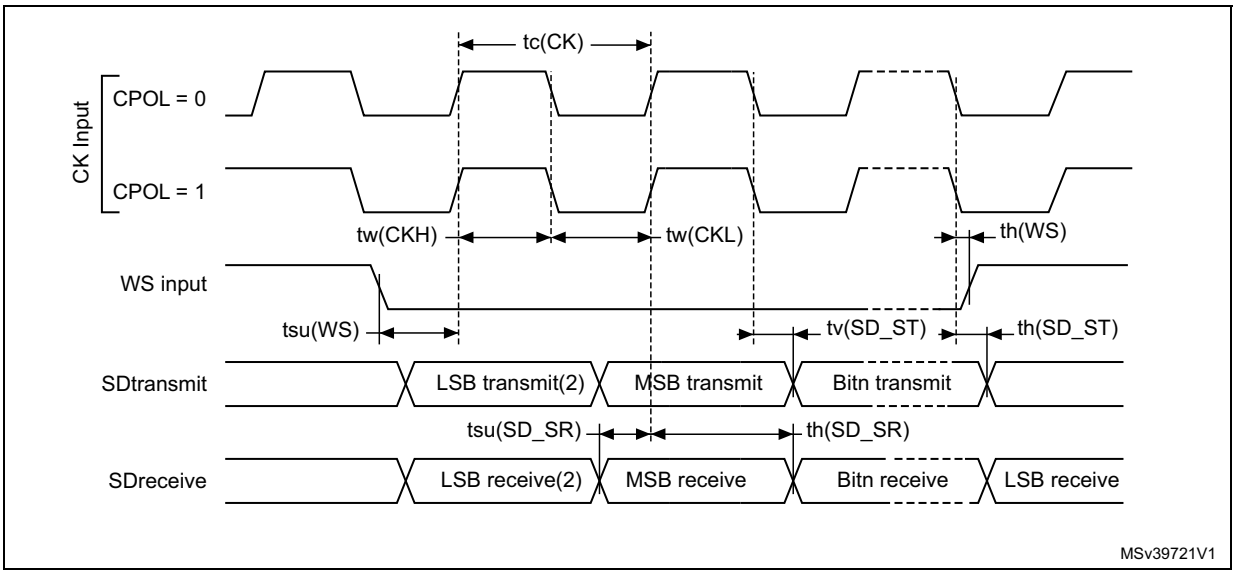
1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Table 64. I^2S characteristics(1) (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
$t_{su(SD\_MR)}$	Data input setup time	Master receiver	6	-	ns
$t_{su(SD\_SR)}$		Slave receiver	2	-	
$t_{h(SD\_MR)}$(2)	Data input hold time	Master receiver	4	-	
$t_{h(SD\_SR)}$(2)		Slave receiver	0.5	-	
$t_{v(SD\_MT)}$(2)	Data output valid time	Master transmitter	-	4	
$t_{v(SD\_ST)}$(2)		Slave transmitter	-	20	
$t_{h(SD\_MT)}$	Data output hold time	Master transmitter	0	-	
$t_{h(SD\_ST)}$		Slave transmitter	13	-	

1. Data based on design simulation and/or characterization results, not tested in production.
2. Depends on f_{PCLK}. For example, if f_{PCLK} = 8 MHz, then T_{PCLK} = 1/f_{PLCLK} = 125 ns.

Figure 32. I^2S slave timing diagram (Philips protocol)

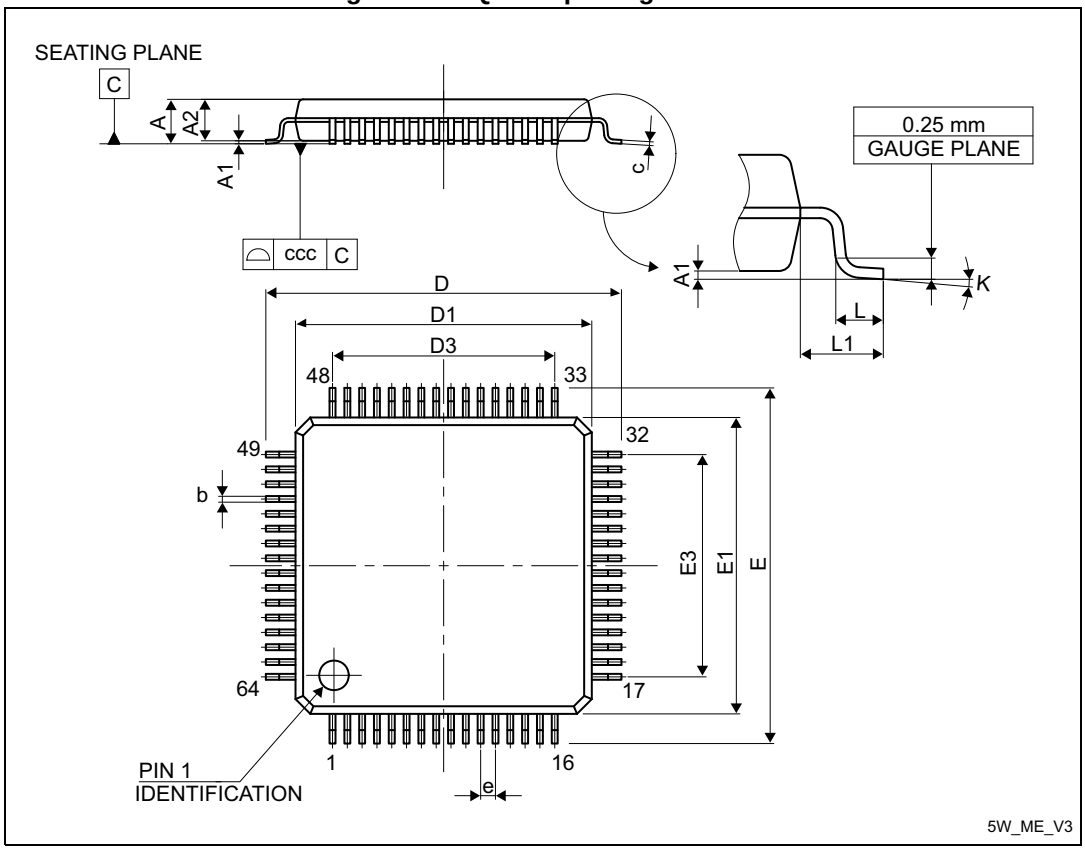


1. Measurement points are done at CMOS levels: 0.3 × V_{DDIOx} and 0.7 × V_{DDIOx}.
2. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

7.2 LQFP64 package information

LQFP64 is a 64-pin, 10 x 10 mm low-profile quad flat package.

Figure 37. LQFP64 package outline



1. Drawing is not to scale.

Table 67. LQFP64 package mechanical data

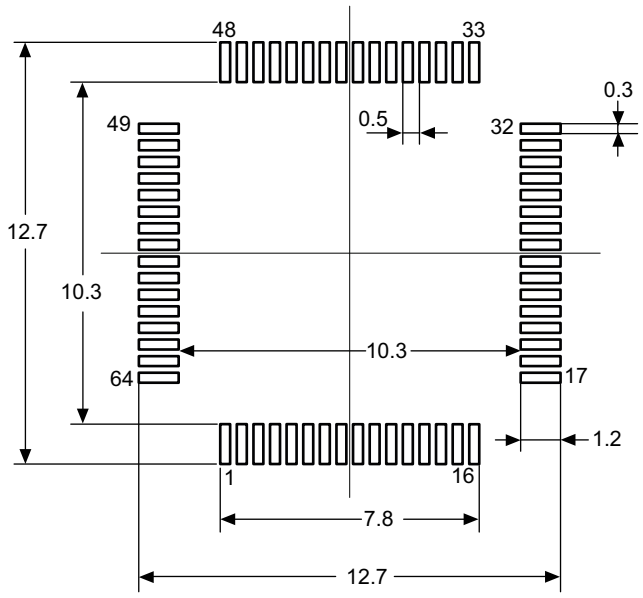
Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-

Table 67. LQFP64 package mechanical data (continued)

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
K	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 38. Recommended footprint for LQFP64 package



1. Dimensions are expressed in millimeters.

Using the values obtained in *Table 74* T_{Jmax} is calculated as follows:

– For LQFP64, 45 °C/W

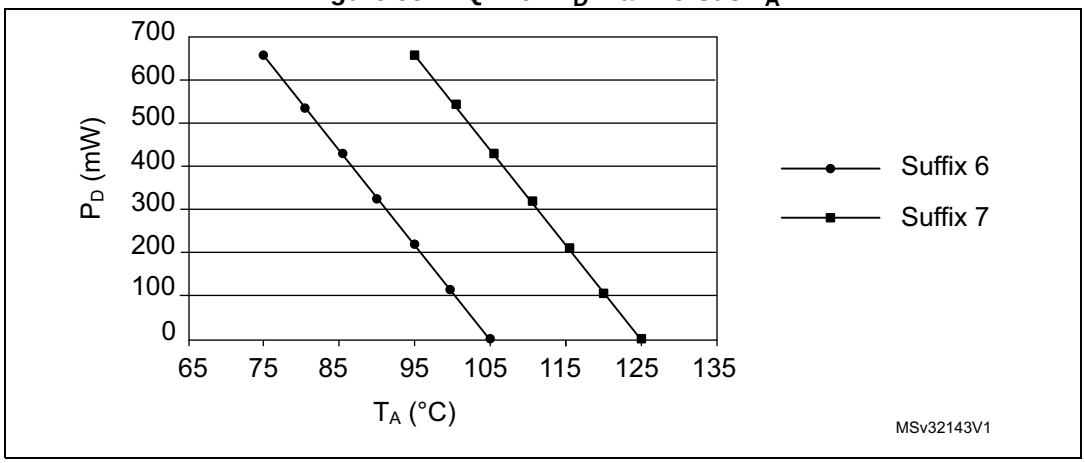
T_{Jmax} = 100 °C + (45 °C/W × 134 mW) = 100 °C + 6.03 °C = 106.03 °C

This is above the range of the suffix 6 version parts (–40 < T_J < 105 °C).

In this case, parts must be ordered at least with the temperature range suffix 7 (see *Section 8: Ordering information*) unless we reduce the power dissipation in order to be able to use suffix 6 parts.

Refer to *Figure 55* to select the required temperature range (suffix 6 or 7) according to your ambient temperature or power requirements.

Figure 55. LQFP64 P_D max versus T_A



9 Revision history

Table 76. Document revision history

Date	Revision	Changes
05-Apr-2012	1	Initial release
25-Apr-2012	2	Updated *Table: STM32F051xx family device features and peripheral counts* for SPI and I^2C in 32-pin package. Corrected Group 3 pin order in *Table: Capacitive sensing GPIOs available on STM32F051xx devices.* Updated the current consumption values in *Section: Electrical characteristics.* Updated *Table: HSI14 oscillator characteristics*
23-Jul-2012	3	Features reorganized and *Figure: Block diagram* structure changed. Added LQFP32 package. Updated *Section: Cyclic redundancy check calculation unit (CRC).* Modified the number of priority levels in *Section: Nested vectored interrupt controller (NVIC).* Added note *3.* for PB2 and PB8, changed TIM2_CH_ETR into TIM2_CH1_ETR in *Table: Pin definitions* and *Table: Alternate functions selected through GPIOA_AFR registers for port A.* Added *Table: Alternate functions selected through GPIOB_AFR registers for port B*. Updated I_{VDD}, I_{VSS}, and $I_{INJ(PIN)}$ in *Table: Current characteristics.* Updated ACC_{HSI} in *Table: HSI oscillator characteristics* and *Table: HSI14 oscillator characteristics.* Updated *Table: I/O current injection susceptibility.* Added BOOT0 input low and high level voltage in *Table: I/O static characteristics.* Modified number of pins in V_{OL} and V_{OH} description, and changed condition for V_{OLFM+} in *Table: Output voltage characteristics.* Changed V_{DD} to V_{DDA} in *Figure: Typical connection diagram using the ADC*. Updated Ts_temp in *Table: TS characteristics.* Updated *Figure: I/O AC characteristics definition*.

Table 76. Document revision history (continued)

Date	Revision	Changes
28-Aug-2015	5	Updated the following: – DAC and power management feature descriptions in *Features* – *Table 2: STM32F051xx family device features and peripheral count* – *Section 3.5.1: Power supply schemes* – *Figure 13: Power supply scheme* – *Table 17: Voltage characteristics* – *Table 20: General operating conditions:* updated the footnote for V_{IN} parameter – *Table 28: Typical and maximum current consumption from the V_{BAT} supply* – *Table 52: ADC characteristics* – *Table 33: High-speed external user clock characteristics*: replaced V_{DD} with V_{DDIOX} – *Table 34: Low-speed external user clock characteristics*: replaced V_{DD} with V_{DDIOX} – *Table 37: HSI oscillator characteristics* and *Figure 19: HSI oscillator accuracy characterization results for soldered parts* – *Table 38: HSI14 oscillator characteristics*: changed the min value for ACC_{HSI14} – *Table 41: Flash memory characteristics*: changed the values for t_{ME} and I_{DD} in write mode – *Table 43: EMS characteristics*: changed the value of V_{EFTB} – *Table 45: ESD absolute maximum ratings* – *Figure 10: STM32F051x8 memory map* – *Figure 21: TC and TTa I/O input characteristics* – *Figure 22: Five volt tolerant (FT and FTf) I/O input characteristics* – *Figure 23: I/O AC characteristics definition* – t_{START} definition in *Table 24: Embedded internal reference voltage* – t_{STAB} characteristics in *Table 52: ADC characteristics* – *Table 56: Comparator characteristics*: changed the description and values for V_{SC}, V_{DDA} and V_{REFINT} parameters. Added *Figure 28: Maximum V_{REFINT} scaler startup time from power down* – *Table 57: TS characteristics:* changed the min value for $T_{S\text{-}temp}$ – *Table 58: V_{BAT} monitoring characteristics:* changed the min value for $T_{S\text{-}vbat}$ and the typical value for R parameters – *Section 6.3.22: Communication interfaces:* updated the description and features in the subsection I^2C interface characteristics – *Table 64: I^2S characteristics:* updated the min values for data input hold time (master and slave receiver)